

Notice of References Cited			Application/Control No.	Applicant(s)/Patent Under Reexamination	
			10/698,578	KUREBAYASHI ET AL.	
Examiner			Art Unit	2627	Page 1 of 1
THOMAS D. ALUNKAL					

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-6,535,470	03-2003	Wu, Shengquan	369/53.3
*	B US-2002/0085470	07-2002	Yokoi, Kenya	369/59.11
*	C US-6,459,666	10-2002	Yokoi, Kenya	369/47.15
*	D US-2003/0086346	05-2003	Fukumoto, Makoto	369/47.53
*	E US-6,563,775	05-2003	Sato, Shinichi	369/47.53
*	F US-5,309,419	05-1994	Koike, Shigeaki	369/47.53
*	G US-2002/0003760	01-2002	Honda, Kazuhiko	369/47.52
*	H US-2002/0141308	10-2002	Matsumoto, Keishi	369/47.53
*	I US-2002/0176338	11-2002	Ushiyama et al.	369/47.53
*	J US-2003/0123352	07-2003	Chen, Chien-Shou	369/47.53
K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	
V	
W	
X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.